VE 320 Summer 2019

Introduction to Semiconductor Devices

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Lecture 4

The semiconductor in equilibrium (Chapter 4)

Carriers in semiconductors: electron and hole

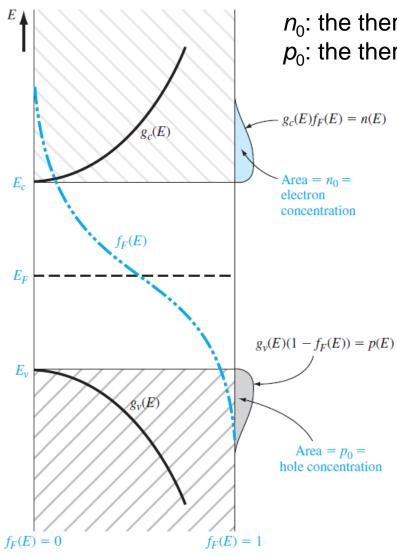
The distribution of electrons in the conduction band (per unit volume and energy) = the density of allowed quantum states × the probability that a state is occupied by an electron

$$n(E) = g_c(E)f_F(E)$$

The distribution of hole in the valence band (per unit volume and energy) = the density of allowed quantum states × the probability that a state is *not* occupied by an electron (or, occupied by a hole)

$$p(E) = g_v(E)[1 - f_F(E)]$$





 n_0 : the thermal-equilibrium concentration of electrons p_0 : the thermal-equilibrium concentration of holes

$$n_0 = \int_{E_c}^{\infty} g_c(E) f_F(E) dE$$

$$p_0 = \int_{-\infty}^{E_v} g_v(E) [1 - f_F(E)] dE$$

$$n_{0} = \int_{E_{c}}^{\infty} g_{c}(E) f_{F}(E) dE$$

$$= \int_{E_{c}}^{+\infty} \frac{1}{1 + \exp\left(\frac{E - E_{F}}{kT}\right)} 4\pi \frac{(2m_{n}^{*})^{\frac{3}{2}}}{h^{3}} (E - E_{c})^{\frac{1}{2}} dE$$

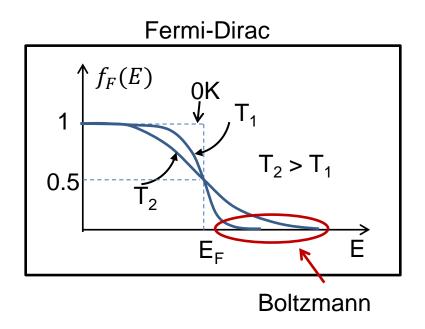
$$if \frac{E - E_F}{kT} > 3 \Leftrightarrow E - E_F > 3kT$$

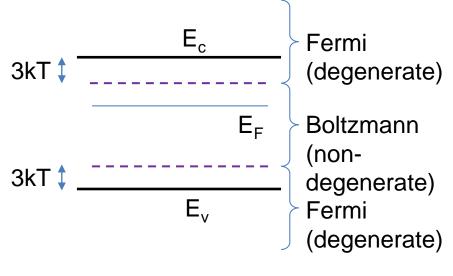
$$f_F(E) = \frac{1}{1 + \exp(\frac{E - E_F}{kT})}$$



Fermi-Dirac Distribution

$$f_F(E) = \exp(\frac{E_F - E}{kT})$$





$$f_F(E) = \frac{1}{1 + \exp(\frac{E - E_F}{kT})}$$



$$f_F(E) = \exp(\frac{E_F - E}{kT})$$

Fermi-Dirac Distribution

$$n_0 = \int_{E_c}^{\infty} g_c(E) f_F(E) dE = 4\pi \frac{(2m_n^*)^{\frac{3}{2}}}{h^3} \int_{E_c}^{+\infty} (E - E_c)^{\frac{1}{2}} \exp\left(\frac{E_F - E}{kT}\right) dE$$

$$\eta = \frac{E - E_c}{kT} = 4\pi \frac{(2m^*kT)^{\frac{3}{2}}}{h^3} \exp\left(\frac{E_F - Ec}{kT}\right) \int_0^{+\infty} \sqrt{\eta} \exp(-\eta) dx$$

$$f_F(E) = \frac{1}{1 + \exp(\frac{E - E_F}{kT})}$$



$$f_F(E) = \exp(\frac{E_F - E}{kT})$$

Fermi-Dirac Distribution

$$n_{0} = \int_{E_{c}}^{\infty} g_{c}(E) f_{F}(E) dE = 4\pi \frac{(2m_{n}^{*})^{\frac{3}{2}}}{h^{3}} \int_{E_{c}}^{+\infty} (E - E_{c})^{\frac{1}{2}} \exp\left(\frac{E_{F} - E}{kT}\right) dE$$

$$\eta = \frac{E - E_{c}}{kT} = 4\pi \frac{(2m^{*}kT)^{\frac{3}{2}}}{h^{3}} \exp\left(\frac{E_{F} - Ec}{kT}\right) \int_{0}^{+\infty} \sqrt{\eta} \exp(-\eta) dx$$

gamma function,
$$=\frac{\sqrt{\pi}}{2}$$

$$f_F(E) = \frac{1}{1 + \exp(\frac{E - E_F}{kT})}$$



$$f_F(E) = \exp(\frac{E_F - E}{kT})$$

Fermi-Dirac Distribution

$$n_0 = \int_{E_c}^{\infty} g_c(E) f_F(E) dE = 4\pi \frac{(2m_n^*)^{\frac{3}{2}}}{h^3} \int_{E_c}^{+\infty} (E - E_c)^{\frac{1}{2}} \exp\left(\frac{E_F - E}{kT}\right) dE$$

$$\eta = \frac{E - E_c}{kT} = 4\pi \frac{(2m^*kT)^{\frac{3}{2}}}{h^3} \exp\left(\frac{E_F - Ec}{kT}\right) \int_0^{+\infty} \sqrt{\eta} \exp(-\eta) dx$$

$$n_0 = 2\left(\frac{2\pi m_n^* kT}{h^2}\right)^{3/2} \exp\left[\frac{-(E_c - E_F)}{kT}\right]$$

$$f_F(E) = \frac{1}{1 + \exp(\frac{E - E_F}{kT})}$$



$$f_F(E) = \exp(\frac{E_F - E}{kT})$$

Fermi-Dirac Distribution

Boltzmann approximation

$$n_0 = 2\left(\frac{2\pi m_n^* kT}{h^2}\right)^{3/2} \exp\left[\frac{-(E_c - E_F)}{kT}\right]$$

$$N_c = 2\left(\frac{2\pi m_n^* kT}{h^2}\right)^{3/2}$$

 $N_c = 2 \left(\frac{2\pi m_n^* kT}{h^2} \right)^{3/2}$ N_c : the effective density of states function in the conduction band

$$n_0 = N_c \exp\left[\frac{-(E_c - E_F)}{kT}\right]$$

$$if \frac{E - E_F}{kT} > 3 \Leftrightarrow E - E_F > 3kT$$

Electron:

$$n_0 = \frac{(2\pi m_n^* kT)^{\frac{3}{2}}}{\hbar^3} \exp\left(\frac{E_F - E_C}{kT}\right) = N_c \exp(\frac{E_F - E_C}{kT})$$

Hole:

$$p_0 = \frac{\left(2\pi m_p^* kT\right)^{\frac{3}{2}}}{\hbar^3} \exp\left(\frac{E_v - E_F}{kT}\right) = N_v \exp\left(\frac{E_v - E_F}{kT}\right)$$

Hole:

 $N_v = 2 \left(\frac{2\pi m_p^* kT}{h^2} \right)^{3/2}$ N_v : the effective density of states function in the valence band.

Intrinsic semiconductor:

$$n_i = p_i$$

 n_i and p_i : intrinsic electron and hole concentration

$$if \frac{E - E_F}{kT} > 3 \Leftrightarrow E - E_F > 3kT$$

Intrinsic Fermi level (E_{Fi}) position:

$$n_{i} = p_{i}$$

$$N_{c} \exp\left[\frac{-(E_{c} - E_{Fi})}{kT}\right] = N_{v} \exp\left[\frac{-(E_{Fi} - E_{v})}{kT}\right]$$

$$E_{Fi} = \frac{1}{2} \left(E_{c} + E_{v}\right) + \frac{1}{2} kT \ln\left(\frac{N_{v}}{N_{c}}\right)$$
Or
$$E_{Fi} = \frac{1}{2} \left(E_{c} + E_{v}\right) + \frac{3}{4} kT \ln\left(\frac{m_{p}^{*}}{m_{n}^{*}}\right)$$
Since
$$\frac{1}{2} \left(E_{c} + E_{v}\right) = E_{\text{midgap}}$$
Then
$$E_{Fi} - E_{\text{midgap}} = \frac{3}{4} kT \ln\left(\frac{m_{p}^{*}}{m_{n}^{*}}\right)$$

$$\frac{E - E_F}{kT} > 3 \Leftrightarrow E - E_F > 3kT \Leftrightarrow N_D, N_A \le 10^{18} cm^{-3}$$

$$n_0 = n_i = N_c \exp\left[\frac{-(E_c - E_{Fi})}{kT}\right]$$
$$p_0 = p_i = n_i = N_v \exp\left[\frac{-(E_{Fi} - E_v)}{kT}\right]$$

For Si at 300K

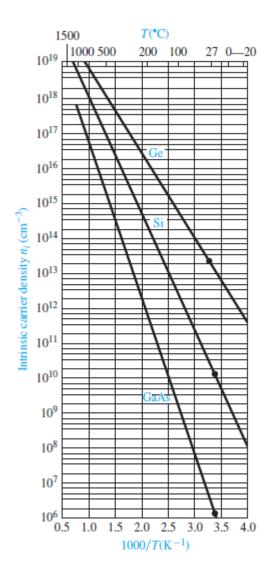
$$N_c \approx 10^{19} cm^{-3}$$

$$N_v\approx 10^{19}cm^{-3}$$

$$n_i \approx 10^{10} cm^{-3}$$

$$n_0 \times p_0 = n_i^2 = N_c N_v \exp\left(\frac{E_v - E_c}{kT}\right) \Rightarrow n_i = \sqrt{N_c N_v} \exp\left(-\frac{E_g}{2kT}\right)$$

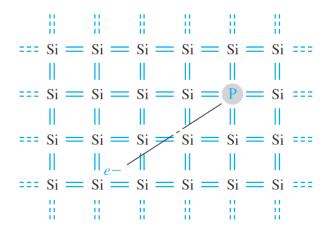
- For a given semiconductor material at a constant temperature, the value of n_i is a constant, and independent of the Fermi energy
- The equations are universal for doped and undoped semiconductors



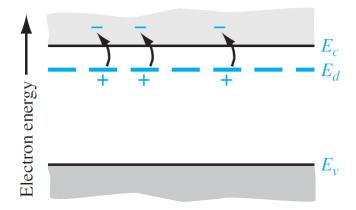
 $n_{\rm i}$ vary over several orders of magnitude as the temperature changes

Review of doping

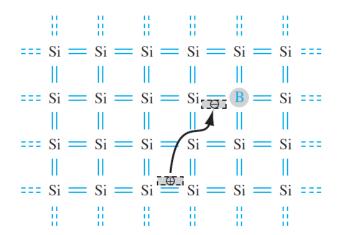
n-type: donor impurity, electrons



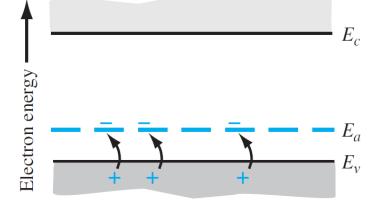
 $E_{\rm d}$: energy state of the donor electron



p-type: acceptor impurity, electrons

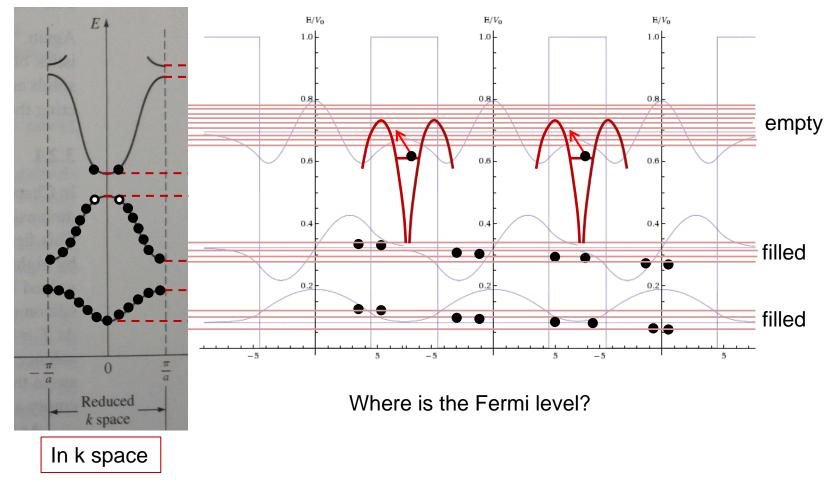


 E_a : energy state of the acceptor



Extrinsic semiconductor: controlled amounts of specific dopant or impurity atoms have been added so that the thermal-equilibrium electron and hole concentrations are different from the intrinsic carrier concentration.

n-type doping



- When $E_F > E_{Fi}$, the electron concentration is larger than the hole concentration
- When $E_F < E_{Fi}$, the hole concentration is larger than the electron concentration
- When the density of electrons is greater than the density of holes, the semiconductor is n type.
- When the density of holes is greater than the density of electrons, the semiconductor is p type.

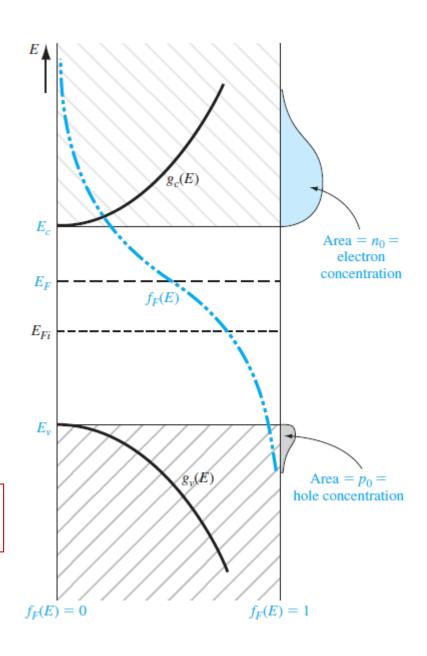
$$n_0 = N_c \exp\left(\frac{E_F - E_c}{kT}\right)$$

If: 1. Doping concentration: N_D, 100% ionized

2. Electrons from thermal are negligible

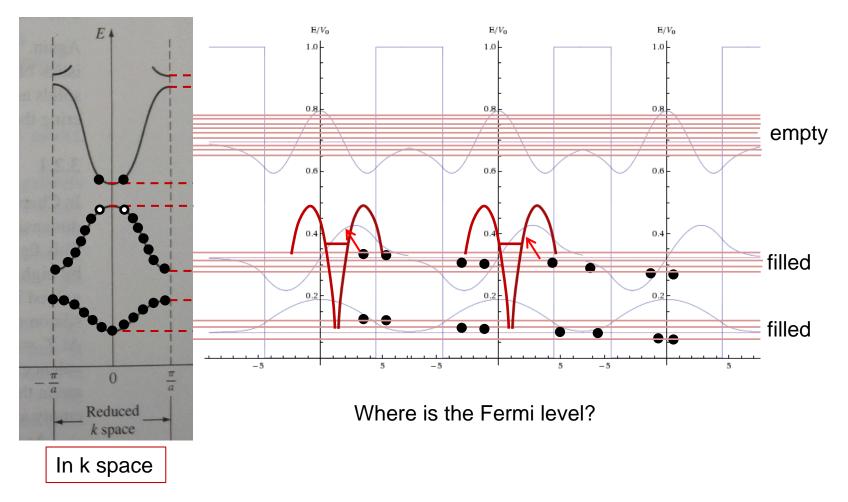
$$n_0 = N_D$$

 $\Rightarrow E_F = E_C - kT ln(\frac{N_C}{N_D})$



Compensate doping

p-type doping



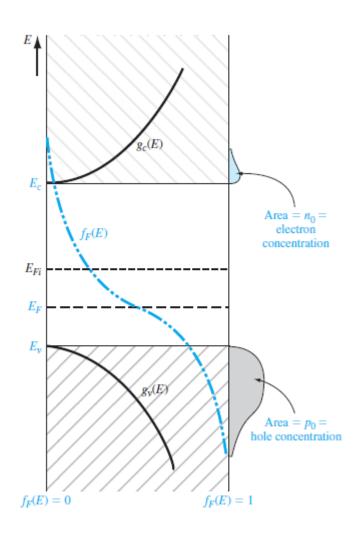
$$p_0 = N_v \exp\left(\frac{E_v - E_F}{kT}\right)$$

If: 1. Doping concentration: N_A, 100% ionized

2. Electrons from thermal are negligible

$$p_0 = N_A$$

$$\Rightarrow E_F = E_v + kT \ln(\frac{N_v}{N_A})$$



- $n_0 > p_0$, the semiconductor is n type
- In an n-type semiconductor, electrons are referred to as the majority carrier and holes as the minority carrier

$$n_{0} = N_{c} \exp\left[\frac{-(E_{c} - E_{Fi}) + (E_{F} - E_{Fi})}{kT}\right] \implies n_{0} = N_{c} \exp\left[\frac{-(E_{c} - E_{Fi})}{kT}\right] \exp\left[\frac{(E_{F} - E_{Fi})}{kT}\right]$$
Remember:
$$n_{i} = N_{c} \exp\left[\frac{-(E_{c} - E_{Fi})}{kT}\right]$$
Then
$$n_{0} = n_{i} \exp\left[\frac{E_{F} - E_{Fi}}{kT}\right]$$
Similarly
$$p_{0} = n_{i} \exp\left[\frac{-(E_{F} - E_{Fi})}{kT}\right]$$

$$n_{0} p_{0} = n_{i}^{2} \text{ if } \frac{E - E_{F}}{kT} > 3 \Leftrightarrow E - E_{F} > 3kT$$

The product of n_0 and p_0 is always a constant for a given semiconductor material at a given temperature in thermal equilibrium

